Claims after this response:

1. (Previously Presented) A method of determining a measurement uncertainty of a selected parameter of a device under test (DUT) when measured by a test system, the combination of said test system and said DUT comprising a plurality of components, each component being characterized by one of a corresponding plurality of values, each value varying in accordance with one of a corresponding plurality of expected probability distributions, said method comprising:

providing a test system model for the combination of said test system and said DUT, said model having a plurality of model elements that affect said measurement uncertainty, each model element representing one of said plurality of components and being characterized by a corresponding one of said plurality of values;

entering the test system model into a simulator;

running a sufficient number of iterations of the test system model on the simulator while randomly varying each of a first portion of the plurality of values within said corresponding probability distributions to produce a statistically significant number of results of the selected parameter; and

evaluating the results to determine the measurement uncertainty of the selected parameter of said DUT.

2. (Original) The method of claim 1 wherein the simulator uses a harmonic balance simulation engine to produce the results.

3. (Original) The method of claim 1 wherein the simulator uses a time-domain simulation engine to produce the results.

4. (Original) The method of claim 1 wherein the simulator uses a linear S-parameter simulation engine to produce the results.

5. (Previously Presented) The method of claim 1 wherein the plurality of probability distributions includes a noise term that represents variations in noise generated by a corresponding component in said combination of said test system and said DUT, said variations in noise being characterized by a corresponding one of said probability distributions.

6. (Previously Presented) The method of claim 1 wherein the plurality of probability distributions includes a test instrument uncertainty term for a test instrument in the test system.

7. (Original) The method of claim 6 wherein the test instrument uncertainty term is selected from the group consisting of a temperature drift uncertainty term, an aging drift uncertainty term, an accuracy uncertainty term, and a repeatability uncertainty term.

8. (Previously Presented) A method of determining a measurement uncertainty of a test system comprising:

developing a test system model having a plurality of uncertainty terms;

entering the test system model into a simulator;

running a sufficient number of iterations of the test system model on the simulator while randomly varying each of a first portion of the plurality of uncertainty terms within probability distributions to produce a statistically significant number of results of a selected parameter; and

evaluating the results to determine a measurement uncertainty of the selected parameter;

wherein the test system model includes a device under test and the step of running the sufficient number of iterations provides a first frequency to the device under test, and the results of the selected parameter are at a second frequency.

9. (Original) The method of claim 8 wherein the second frequency is a harmonic of the first frequency.

10. (Original) The method of claim 8 wherein the second frequency is a mixing product of the first frequency and a third frequency.

11. (Original) The method of claim 1 wherein the test system model includes a test instrument as a device under test.

12. (Previously Presented) A method of determining a measurement uncertainty of a test system comprising:

developing a test system model having a plurality of uncertainty terms;

entering the test system model into a simulator;

running a sufficient number of iterations of the test system model on the simulator while randomly varying each of a first portion of the plurality of uncertainty terms within probability distributions to produce a statistically significant number of results of a selected parameter; and

evaluating the results to determine a measurement uncertainty of the selected parameter;

wherein the test system model includes a test fixture comprising a plurality of switches and a plurality of cables.

13. (Original) The method of claim 1 wherein the step of running occurs at a first operating condition and further comprising steps of:

running a sufficient number of iterations of the test system model on the simulator at a second operating condition while randomly varying each of the first portion of the plurality of uncertainty terms within probability distributions to produce a statistically significant number of second results of the selected parameter; and

evaluating the second results to determine a second measurement uncertainty of the selected parameter.

14. (Original) The method of claim 1 wherein the step of running is done using a first type of simulation engine and further comprising steps of:

running a second sufficient number of iterations of the test system model on the simulator using a second type of simulation engine while randomly varying each of the first portion of the plurality of uncertainty terms within probability distributions to produce a statistically significant number of second results of a second selected parameter; and

evaluating the second results to determine a second measurement uncertainty of the second selected parameter.

15. (Original) The method of claim 1 further comprising a step of

developing a computer-readable library of test system components with uncertainty terms, and wherein the step of entering the test system model into the simulator includes loading uncertainty terms associated with the test system components from the computer-readable library.

16. (Previously Presented) The method of claim 1 wherein the step of providing the test system model includes automatically generating system specifications.